



Description

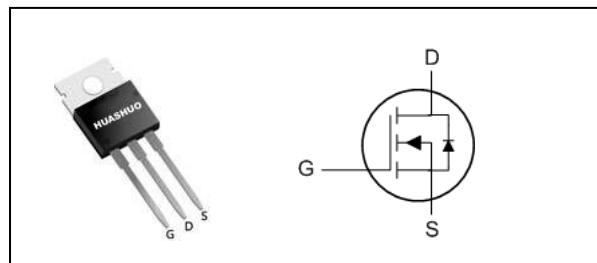
HSP8N50 is Fortunatus high voltage MOSFET family based on advanced planar stripe DMOS technology. This advanced MOSFET family has optimized on-state resistance, and also provides superior switching performance and higher avalanche energy strength. This device family is suitable for high efficiency switch mode power supplies.

- High Efficiency
- 100% EAS Guaranteed
- Improved dv/dt,di/dt capability
- Green Device
- Low Crss(typical 10pF)

Product Summary

V _{DS}	500	V
R _{DS(ON),typ}	850	mΩ
I _D	8	A

TO220 Pin Configuration



Absolute Maximum Ratings

Symbol	Parameter	Rating	Units
V _{DS}	Drain-Source Voltage	500	V
V _{Gs}	Gate-Source Voltage	±30	V
I _D @T _c =25°C	Continuous Drain Current, V _{Gs} @ 10V ₁	8	A
I _D @T _c =100°C	Continuous Drain Current, V _{Gs} @ 10V ₁	5.1	A
I _{DM}	Pulsed Drain Current ²	32	A
Dv/dt	Peak Diode Recovery dv/dt (Note3)	3.5	V/ns
EAS	Single Pulse Avalanche Energy ³	320	mJ
P _D @T _c =25°C	Total Power Dissipation ⁴	142	W
T _{STG}	Storage Temperature Range	-55 to 150	°C
T _J	Operating Junction Temperature Range	-55 to 150	°C

Thermal Data

Symbol	Parameter	Typ.	Max.	Unit
R _{θJA}	Thermal Resistance Junction-Ambient ₁	---	62.5	°C/W
R _{θJC}	Thermal Resistance Junction-Case ₁	---	0.88	°C/W



Electrical Characteristics ($T_J=25\text{ }^{\circ}\text{C}$, unless otherwise noted)

Symbol	Parameter	Conditions	Min.	Typ.	Max.	Unit
BV_{DSS}	Drain-Source Breakdown Voltage	$V_{GS}=0\text{V}$, $I_D=250\mu\text{A}$	500	---	---	V
$\Delta BV_{DSS}/\Delta T_J$	$BVDSS$ Temperature Coefficient	Reference to $25\text{ }^{\circ}\text{C}$, $I_D=1\text{mA}$	---	0.0193	---	$\text{V}/^{\circ}\text{C}$
$R_{DS(ON)}$	Static Drain-Source On-Resistance ₂	$V_{GS}=10\text{V}$, $I_D=4\text{A}$	---	---	850	$\text{m}\Omega$
$V_{GS(th)}$	Gate Threshold Voltage	$V_{GS}=V_{DS}$, $I_D=250\mu\text{A}$	2	---	4	V
$\Delta V_{GS(th)}$	$V_{GS(th)}$ Temperature Coefficient		---	-3.97	---	$\text{mV}/^{\circ}\text{C}$
I_{DSS}	Drain-Source Leakage Current	$V_{DS}=500\text{V}$, $V_{GS}=0\text{V}$, $T_J=25\text{ }^{\circ}\text{C}$	---	---	1	μA
		$V_{DS}=400\text{V}$, $V_{GS}=0\text{V}$, $T_J=125\text{ }^{\circ}\text{C}$	---	---	100	
G_{fs}	Forward Transconductance (Note4)	$V_{DS}=50\text{V}$, $I_D=4\text{A}$	---	7.2	---	S
I_{GSS}	Gate-Source Leakage Current	$V_{GS}=\pm 30\text{V}$, $V_{DS}=0\text{V}$	---	---	± 100	nA
Q_g	Total Gate Charge (4.5V)	$V_{DD}=400\text{V}$, $V_{GS}=10\text{V}$, $I_D=8\text{A}$	---	23	---	nC
Q_{gs}	Gate-Source Charge		---	6.2	---	
Q_{gd}	Gate-Drain Charge		---	11	---	
$T_{d(on)}$	Turn-On Delay Time	$V_{DD}=250\text{V}$, $V_{GS}=10\text{V}$, $R_G=10\Omega$	---	24	---	ns
T_r	Rise Time		---	16	---	
$T_{d(off)}$	Turn-Off Delay Time		---	40	---	
T_f	Fall Time		---	16	---	
C_{iss}	Input Capacitance	$V_{DS}=25\text{V}$, $V_{GS}=0\text{V}$, $f=1\text{MHz}$	---	980	---	pF
C_{oss}	Output Capacitance		---	110	---	
C_{rss}	Reverse Transfer Capacitance		---	10	---	

Diode Characteristics

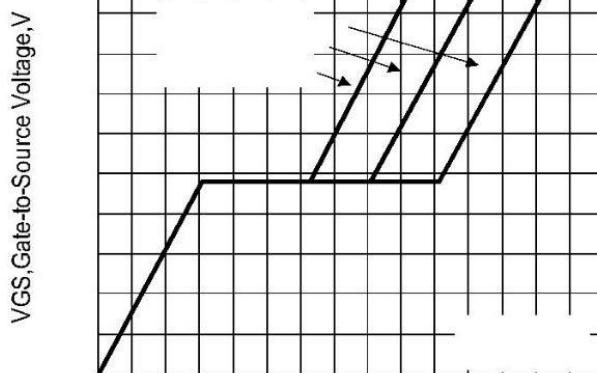
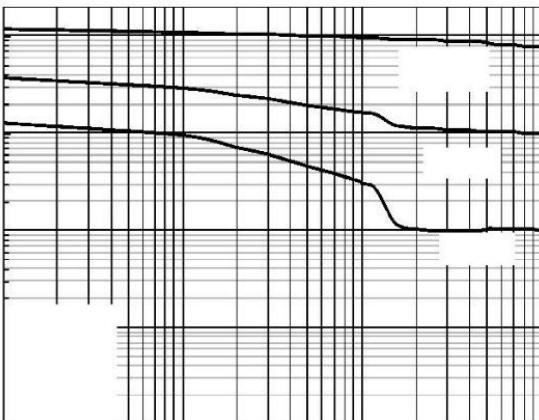
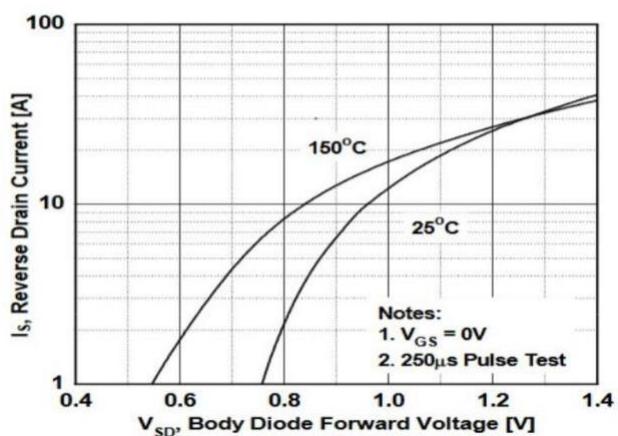
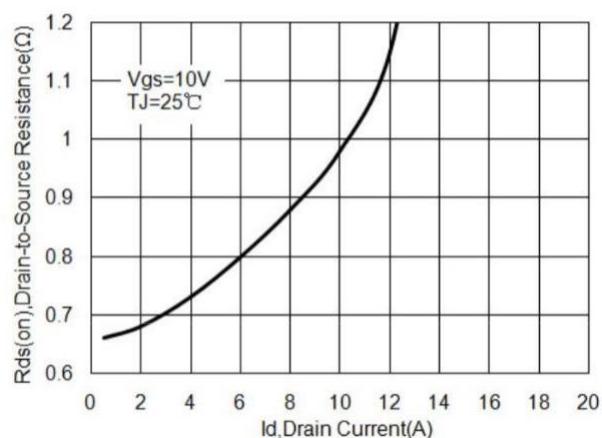
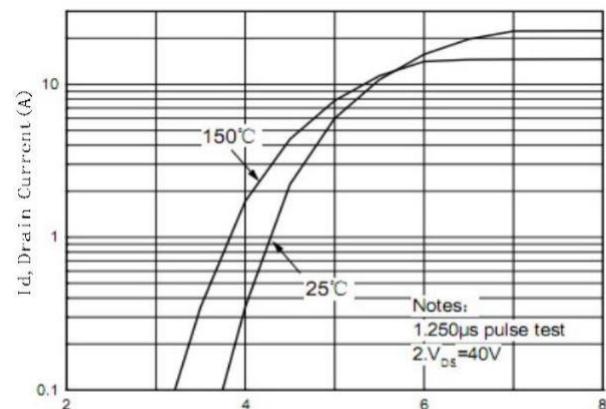
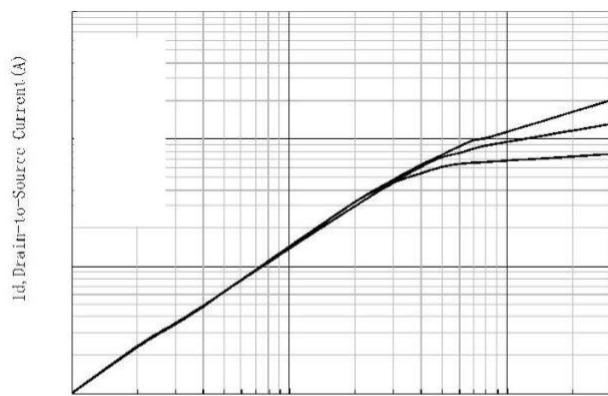
Symbol	Parameter	Conditions	Min.	Typ.	Max.	Unit
I_s	Continuous Source Current _{1,5}	$V_G=V_D=0\text{V}$, Force Current	---	---	8	A
I_{SM}	Pulsed Source Current _{2,5}		---	---	32	A
V_{SD}	Diode Forward Voltage ₂	$V_{GS}=0\text{V}$, $I_s=1\text{A}$, $T_J=25\text{ }^{\circ}\text{C}$	---	---	1.4	V
t_{rr}	Reverse Recovery Time	$I_F=8\text{A}$, $dI/dt=100\text{A}/\mu\text{s}$, $T_J=25\text{ }^{\circ}\text{C}$	---	360	---	ns
Q_{rr}	Reverse Recovery Charge		---	3.5	---	nC



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HSP8N50

Typical Characteristics



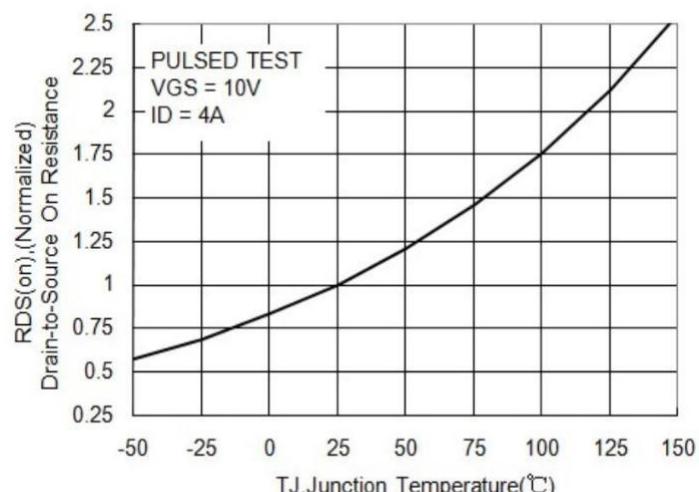
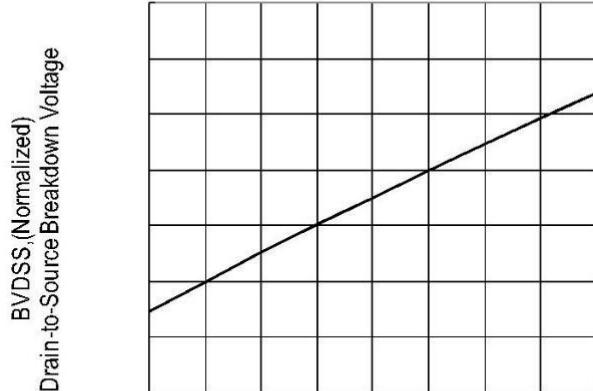


Figure 8. On-Resistance Variation with Temperature

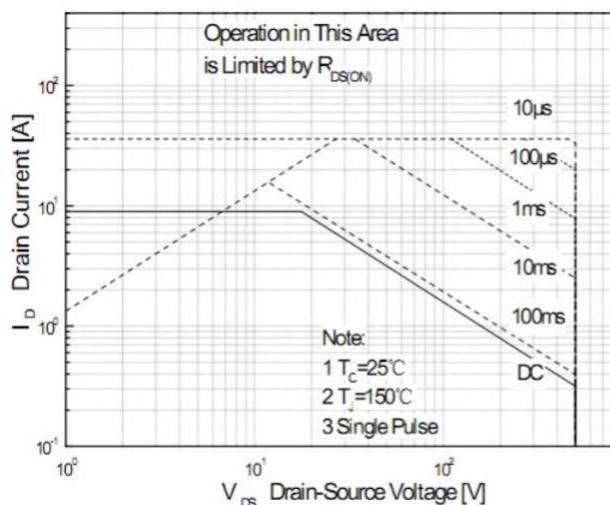


Figure 9. Maximum Safe Operating Area
For FX8N50BUG/DG/PG

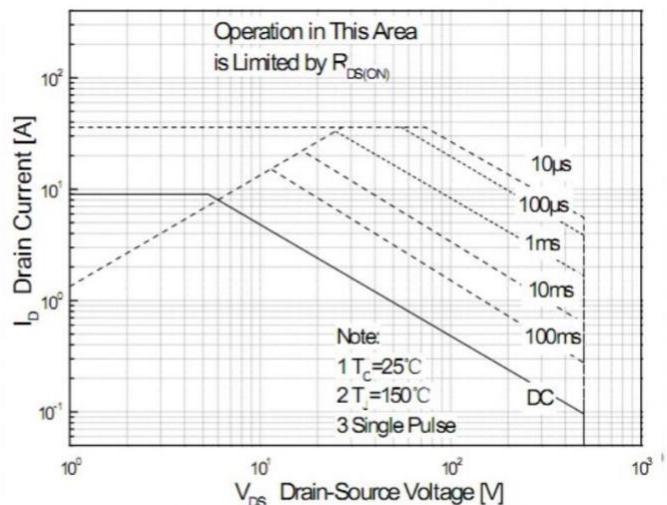
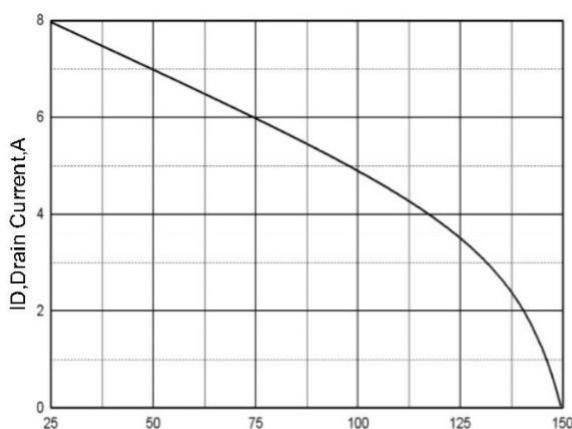
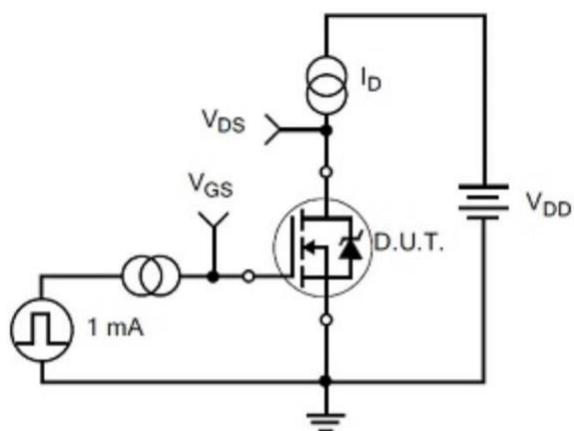
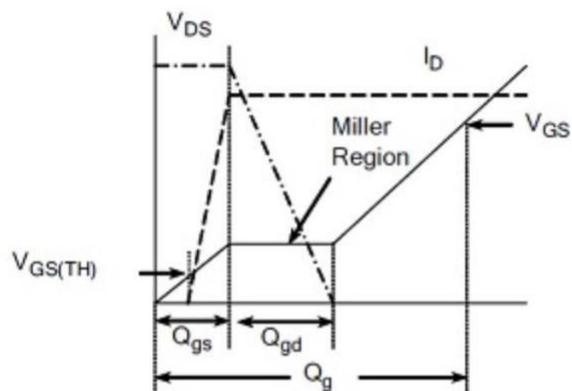


Figure 9. Maximum Safe Operating Area
For FX8N50BFG

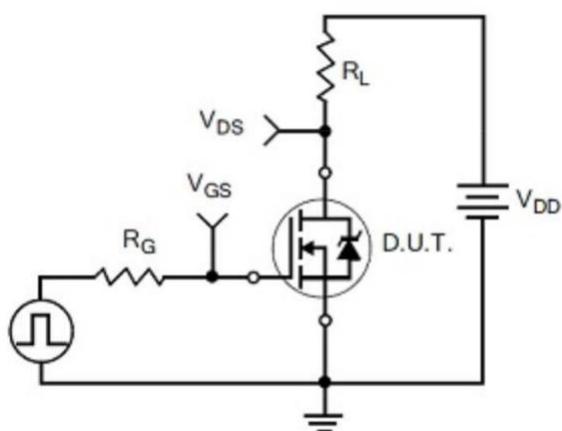




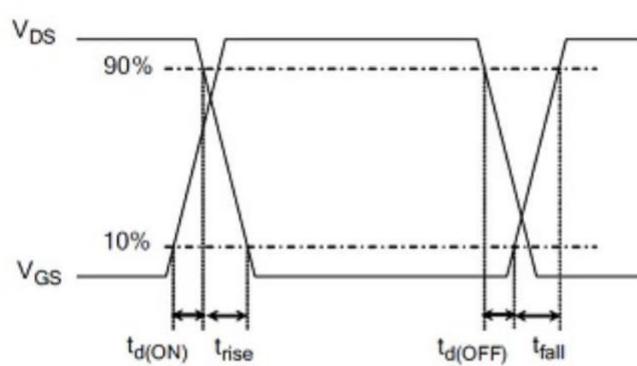
Gate Charge Test Circuit



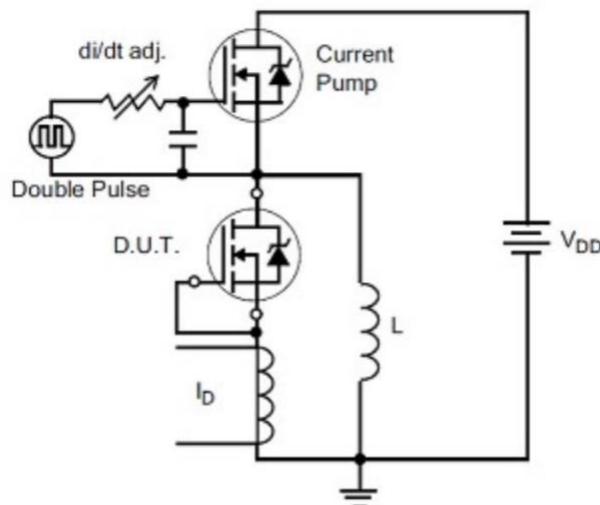
Gate Charge Waveform



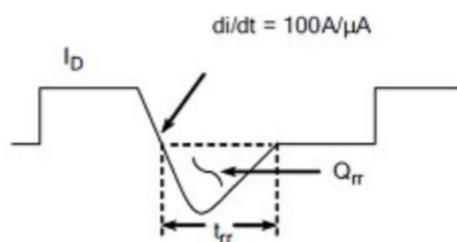
Resistive Switching Test Circuit



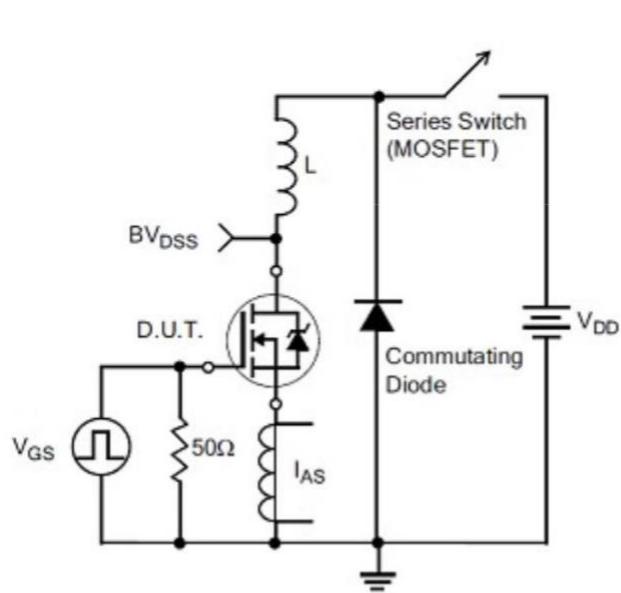
Resistive Switching Waveforms



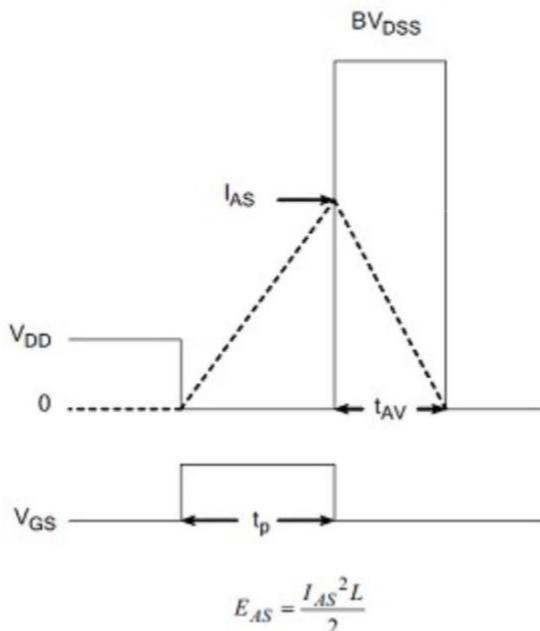
Diode Reverse Recovery Test Circuit



Diode Reverse Recovery Waveform



Unclamped Inductive Switching Test Circuit



Unclamped Inductive Switching Waveforms

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